

LPX: a low-power processor with a locally asynchronous (IPCMOS) execute pipe**

Alper Buyuktosunoglu**, Michael Gschwind, Pradip Bose, Hans Jacobson, Philip Emma
IBM T. J. Watson Research Center
Yorktown Heights, NY

** contributors to LPX project (prior and current):

P. Bose, D. Brooks, A. Buyuktosunoglu, P. Cook, K. Das, P. Emma, M. Gschwind, H. Jacobson,
 P. Kudva, S. Schuster, J. Smith, V. Srinivasan, V. Zyuban: IBM. T. J. Watson Research Center.

D. Albonesi and S. Dwarkadas: Univ. of Rochester, NY. K. Das: summer intern from U of Michigan
 T. Karkhanis: summer intern from U of Wisconsin
 J. Smith: was on sabbatical from U of Wisconsin

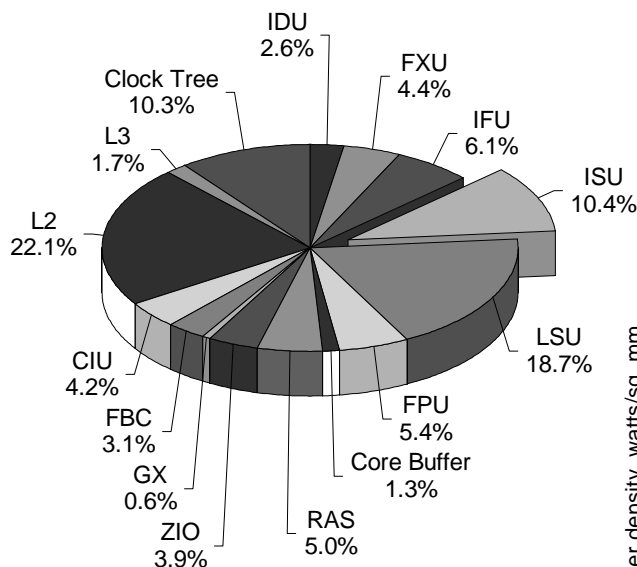
++Alper Buyuktosunoglu is also a Ph.D student
 at University of Rochester, NY



MICRO-35 Tutorial, November 18, 2002, Istanbul, Turkey.

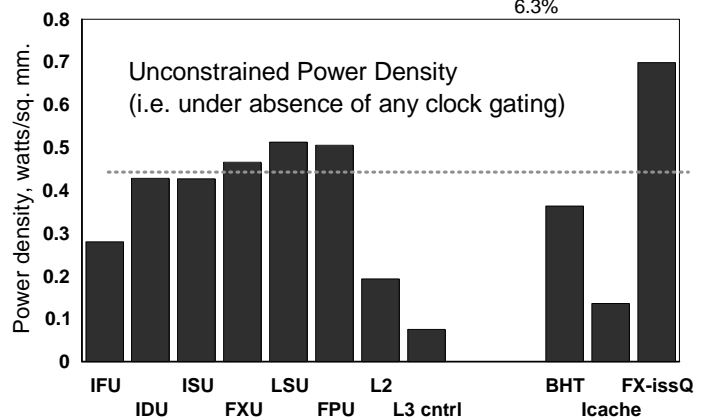
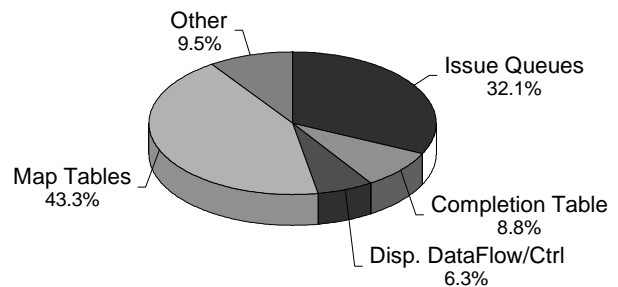
Current Generation High-End Processor Power Profile

(Quoted from prior published PACS-02 paper)



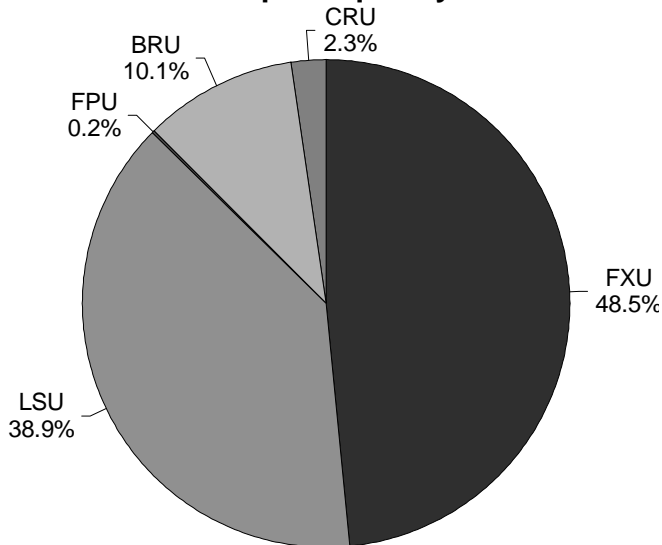
(Non-validated, pre-silicon,
 POWER4-like superscalar design)

Instruction Seq. Unit Power Breakdown



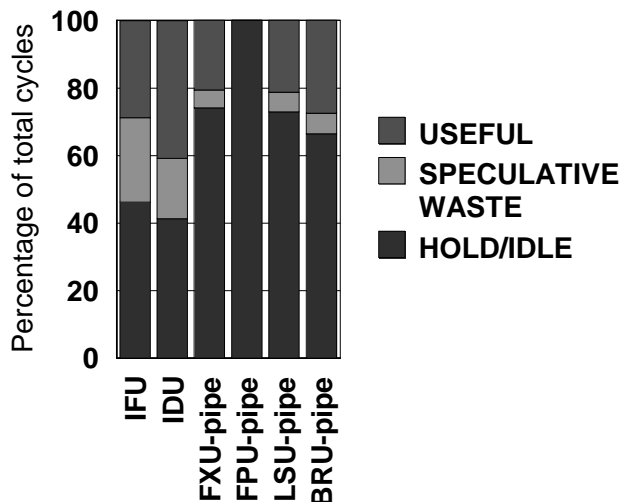
Energy Waste in High-End Superscalar: Non-Gated

TPCC trace iops frequency



Unit Utilization Stack

(Execution Pipes Only)

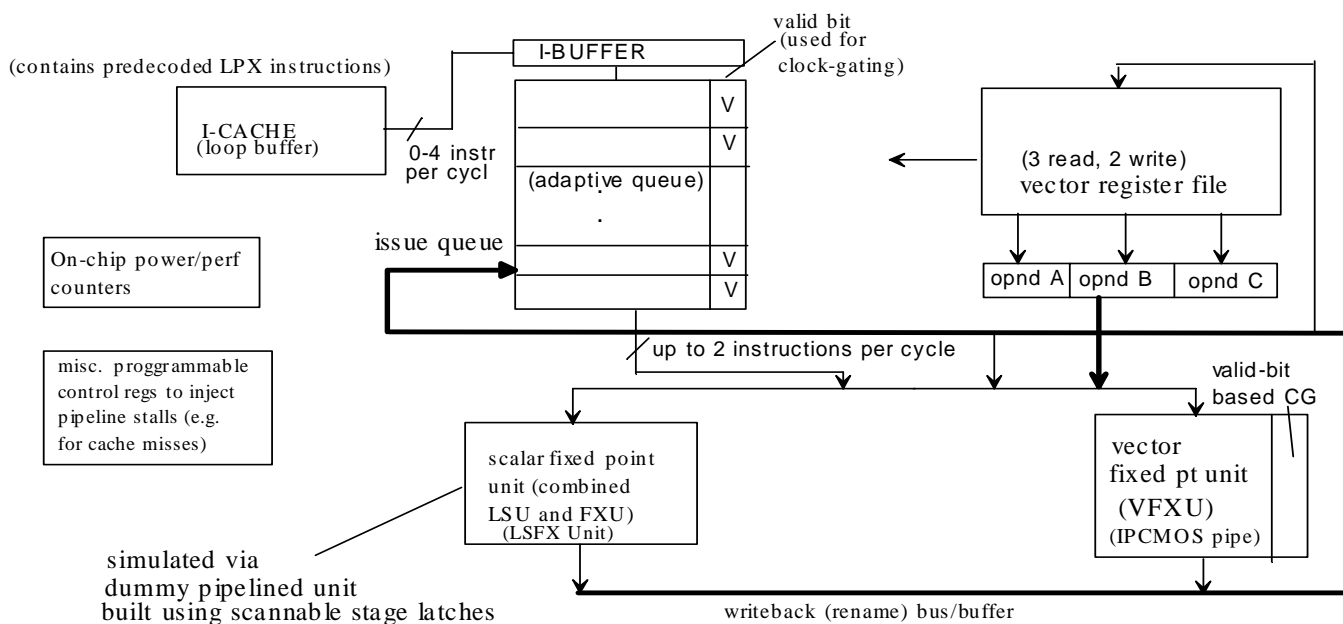


Coarse-grained clock gating opportunities

Pre-silicon, non-gated POWER4-like simulation mode results

LPX: High-Level Block Diagram

(Goal: demonstrate 5X power density reduction with *at most* 5% IPC performance hit)



Key Design Ideas in LPX

■ Microarchitecture-level

- ▶ adaptive resource sizing: dynamic, application-driven;
- ▶ dynamic ifetch throttling: set of simple fetch-gating heuristics;
- ▶ *new: combined fetch-gating + adaptive queues* (ongoing research)
- ▶ microarchitectural support for clock gating: coarse-grain, fine-grain; "on-demand"
- ▶ on-chip counter architecture for power/perf monitoring and feedback

■ Logic/circuit-level

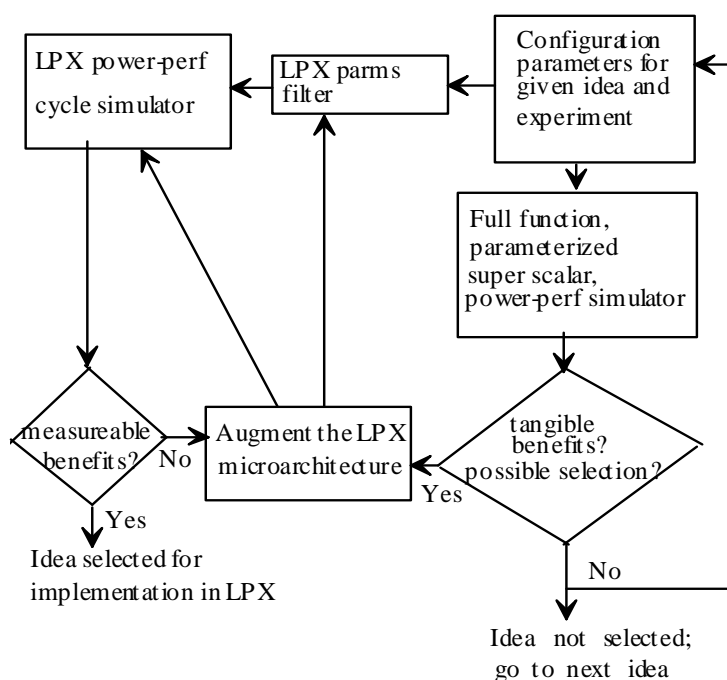
- ▶ adaptive clocking: save power, maintain performance
 - locally generated, enabled by data (IPCMOS)
 - synchronous clock-gating: coarse and fine-grain (ISP)
 - variable or phased step-up/down: on-demand clock-gating (OD-CG)
 - Vdd-gating for banked issue queue (new addition - being incorporated)
- ▶ power-efficient CAM/RAM structures - research only

note: not all features above will be implemented; but are studied in high-level microarchitectural research work (simulation-based)

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

Methodology for LPX Definition and Tuning



- Idea selected must have potential power-perf "worth" based on:

- *simulation "in the large".*

- Basic idea is adapted to a much simpler hardware heuristic, appropriate for LPX:

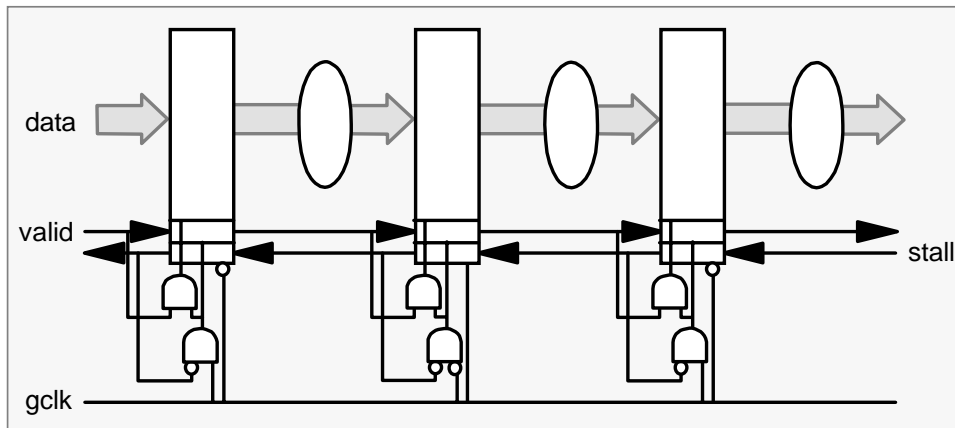
- *simulation and prototyping "in the small".*

- Extensive circuit simulation to validate power savings and overhead:

- *done before microarch. def.*

Interlocked Synchronous Pipelines (ISP)

PIPELINE STRUCTURE



(Paper accepted for publication in ASYNC'2002:
H. Jacobson et al.)

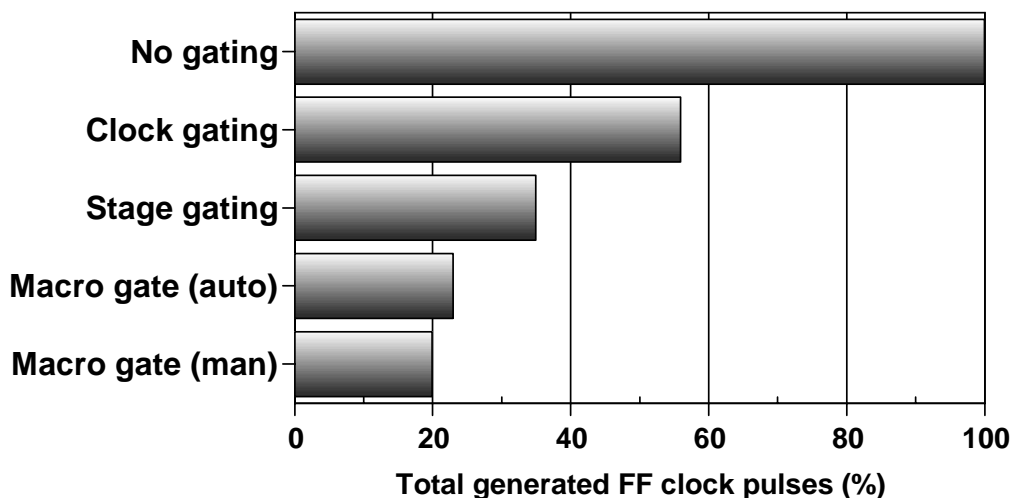
- Clock gating is performed local to each stage on a cycle basis
- Clock is gated on both invalid data and stall conditions
- ISPs are testable using standard LSSD techniques

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

ISP Results

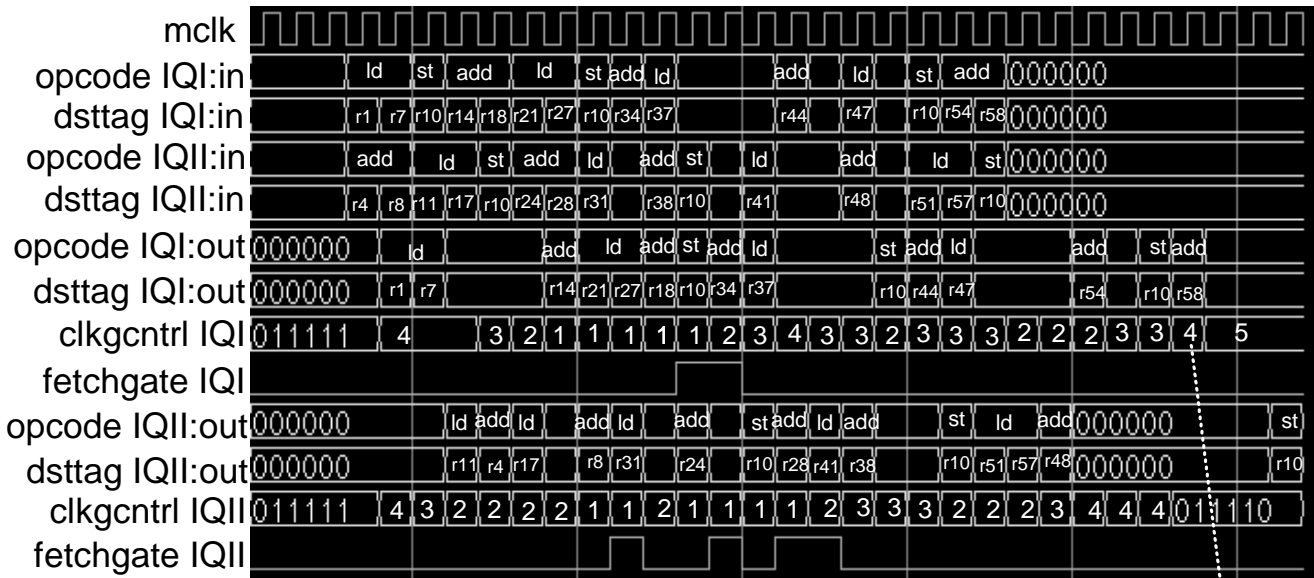
Clock Gating Results: FPU Datapath (RTL level)



- ISP savings also being tested with LPX timer

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

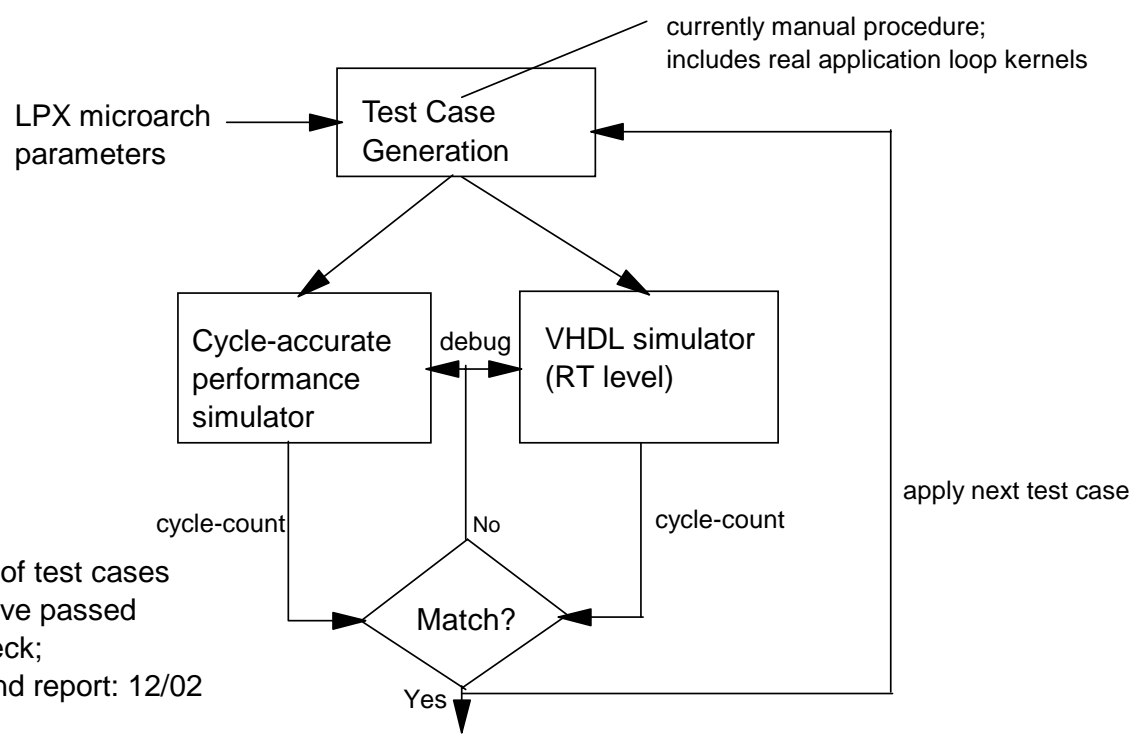


vector add loop:
 ld r1 r2 r3 r r → preset ready bits
 add r4 r1 r6 nr r → mimic the rename
 ld r7 r2 r5 r r (r: ready, nr: not ready)
 add r8 r4 r7 nr nr
 st r10 r8 r9 nr r

of entries
clock gated

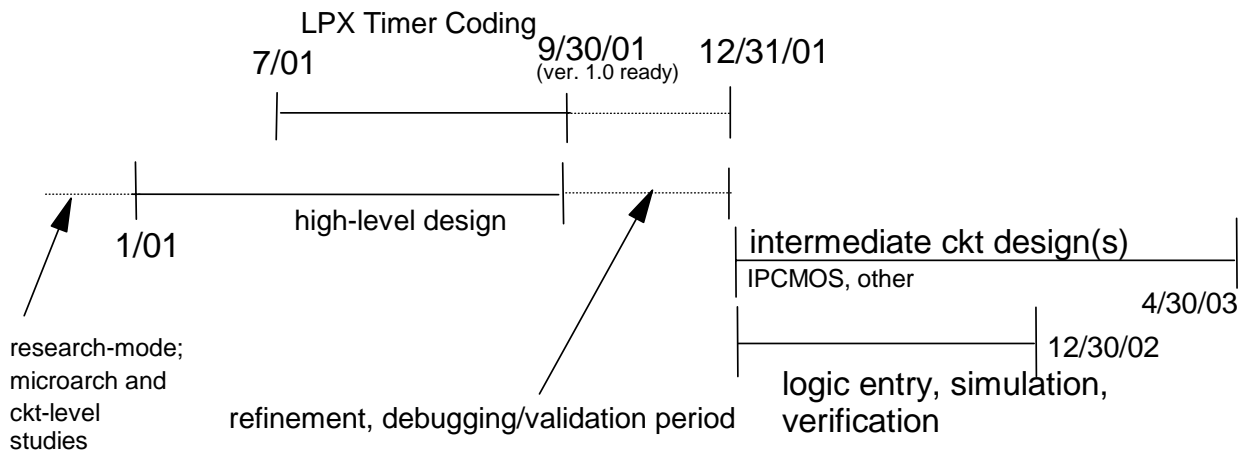
LPX VHDL results

Validation Methodology



Status: 90 % of test cases developed have passed validation check; completion and report: 12/02

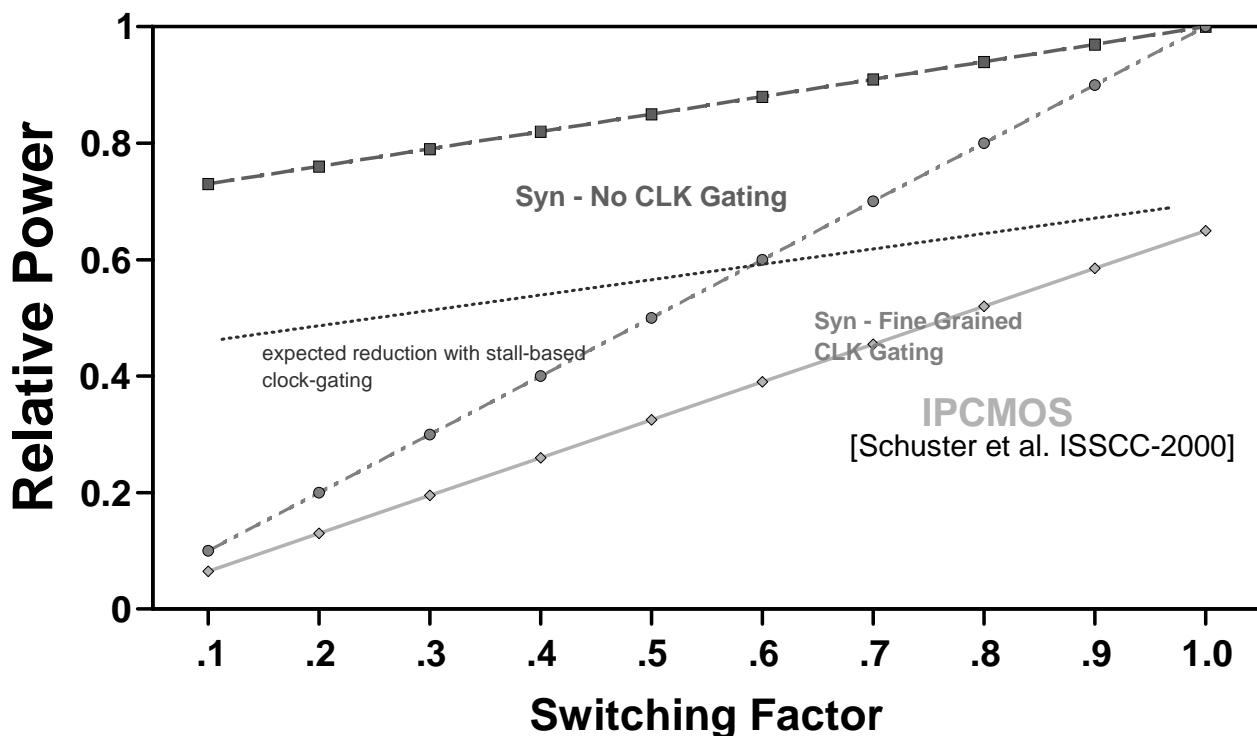
LPX Design Schedule (2001-03)



Physical design, implementation phase: through 2003

Power versus Switching Factor

(assuming 70% of power in clocks and latches as in POWER4)



Conclusion

SUMMARY:

- Power density limits in high-end processors
 - ✓ power-aware microarchitecture + advanced clocking/ckt techniques
- LPX: a small research processor prototype to validate newer ideas
 - ✓ high-level microarchitecture definition and analysis reported
 - ✓ processor is scheduled for tapeout in 2003

FUTURE/ONGOING WORK:

- Logic design/VHDL simulation and verification: by year-end 2002
- Power-efficient cache design research for LPX follow-on chip
- Power monitoring/measurement hardware architecture
- Measurement-based calibration of pre-silicon energy models

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

Low Power Locally Asynchronous Interlocked Pipelined CMOS (IPCMOS) Clock Circuits Operating at 3.3-4.5GHz (0.18 micron; 1999)

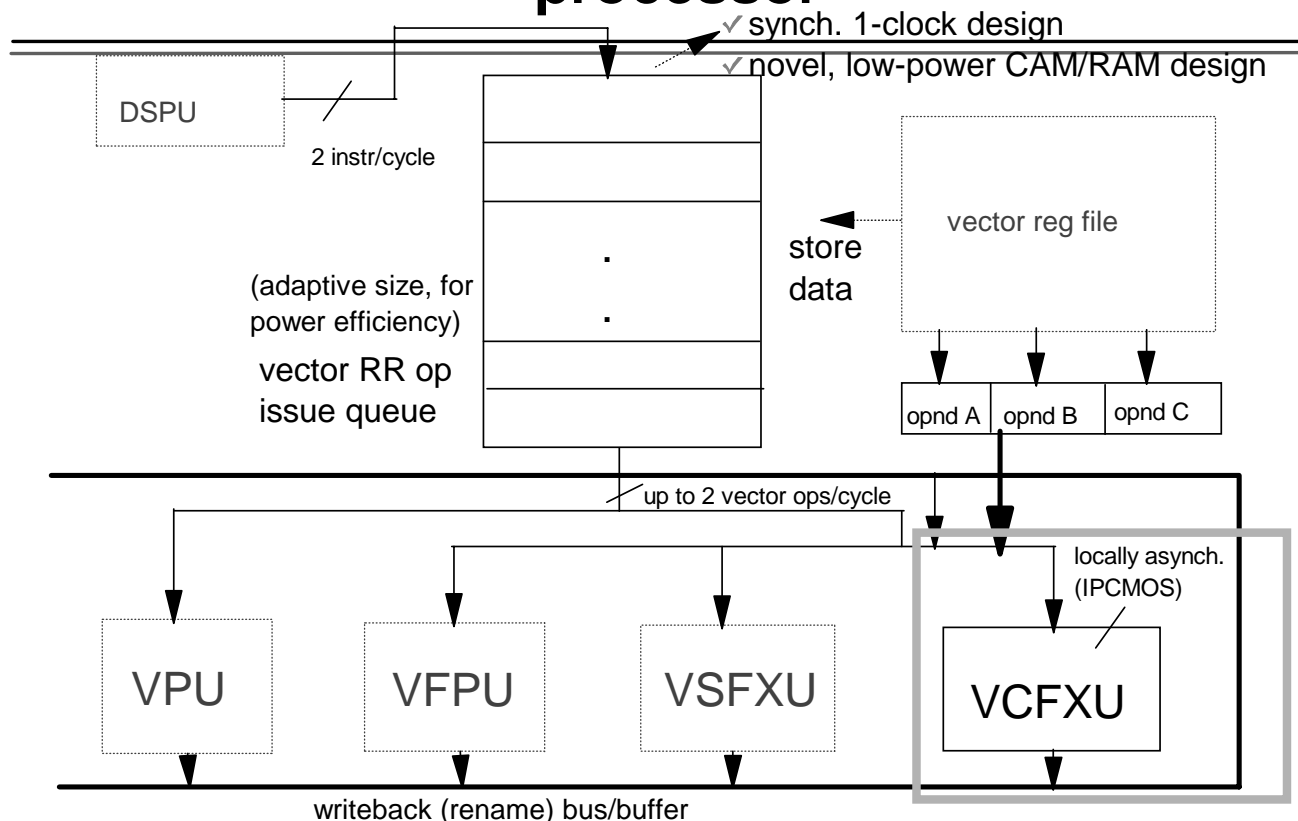
Stan Schuster, Pete Cook

IBM Research Center
Yorktown Heights, NY

IPCMOS Team Members

- Concepts
 - ▶ Stan Schuster, Pete Cook
- Test Site
 - ▶ Stan Schuster, Bill Reohr, Pete Cook, Dave Heidel, Mike Immediato, Keith Jenkins

LPX: a low power issue-execute VMX processor

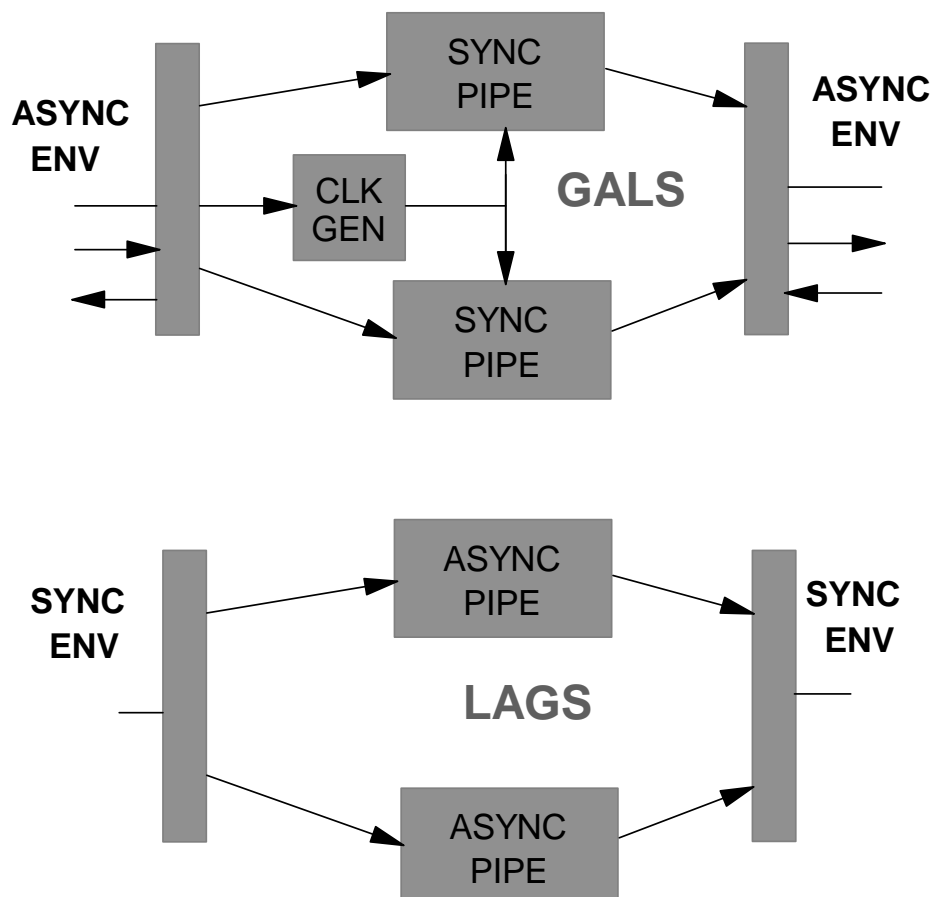


Early Work

- Communications protocols
- Sutherland paper on "Micropipelines" in the Communications of the ACM 1989
- Muller C-element described by Mead and Conway 1980
- Williams et al. "-- 160ns 54-b CMOS Divider" JSSC 11/91
- Chappell et al. "-- SRAM with Fully Pipelined Architecture" JSSC 11/91
- Proceedings of the IEEE Special Issue on Asynchronous Circuits and Systems 2/99

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners



MICRO-35 Tutorial PAMs, 2002

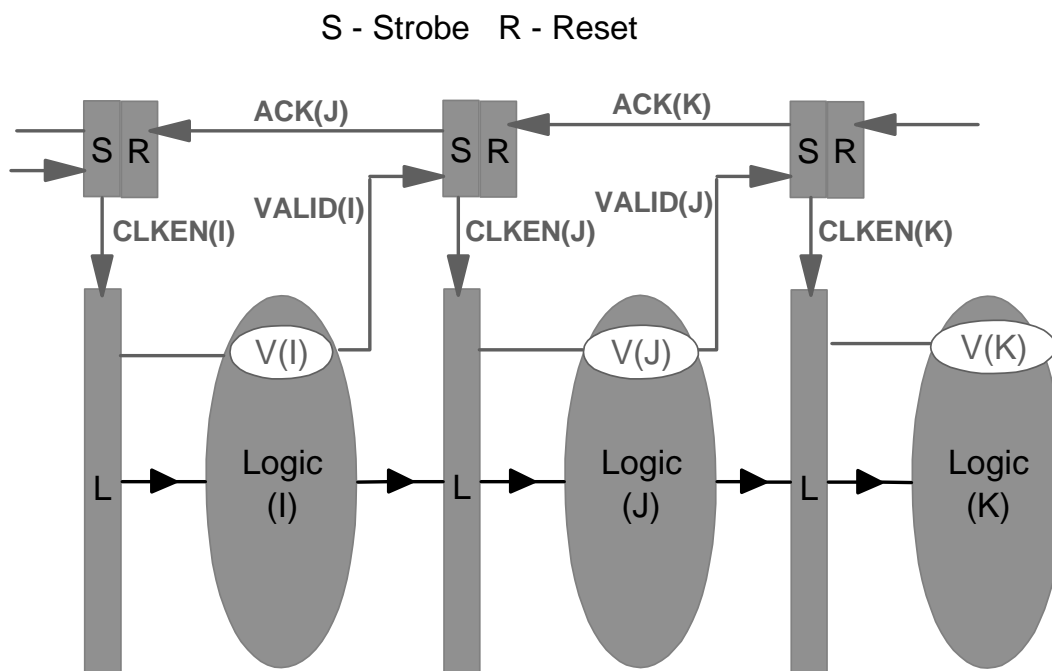
IBM T. J. Watson Research Center and university partners

Why IPCMOS?

- Lower Power
 - ▶ Clocks enabled only when operation to perform
 - ▶ Single stage transparent latch
- Higher speed
 - ▶ Single stage transparent latch
 - ▶ Interlocked local clocks
- Circuits deal with global timing issues
 - ▶ Delay variations from power supply noise
 - ▶ Delay variations from chip parametrics
- Asynchronous to synchronous interface possible
- Both ac and dc testing possible

MICRO-35 Tutorial PAMs, 2002

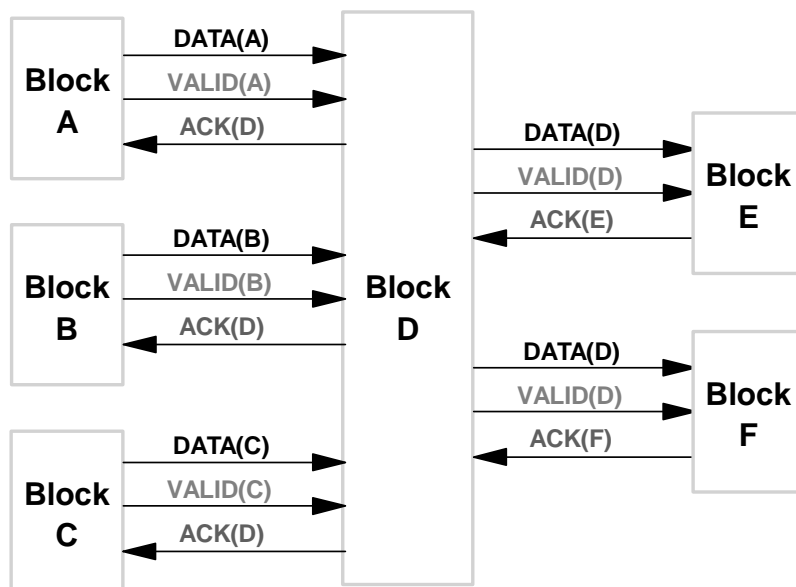
IBM T. J. Watson Research Center and university partners



IPCMOS Interlocking

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners



Interlocking at the Block Level

IPCMOS Circuits

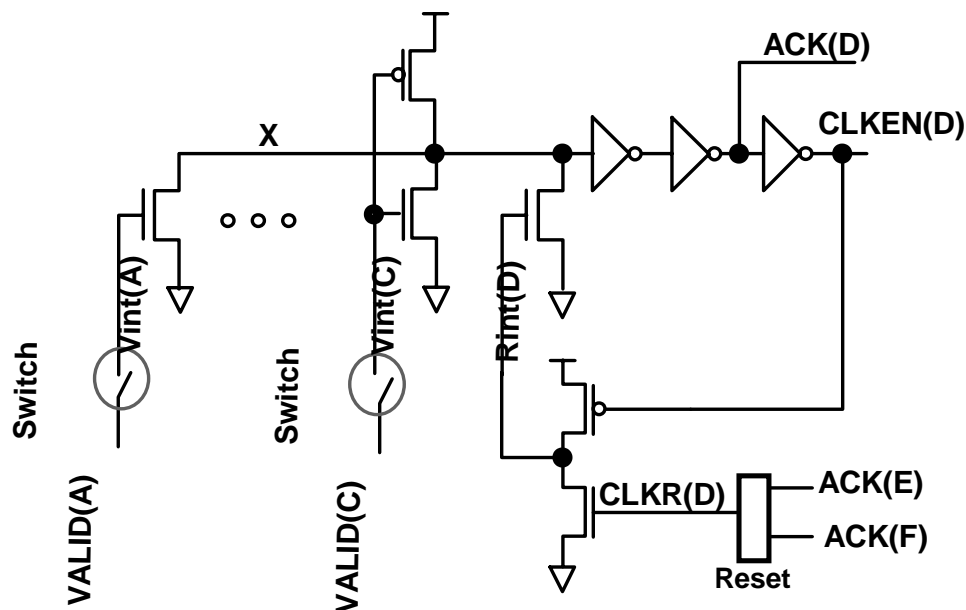
- Circuits are key to achieving high speed!
- Key IPCMOS Circuits
 - ▶ Strobe
 - ▶ Reset
 - ▶ Latch
 - ▶ Valid

Strobe

- Unique "AND" circuit
 - ▶ Detects all inputs low
 - ▶ Detects all inputs have gone high
- Keeps track of cycles on inputs and outputs
- Switch between internal and external inputs minimizes interlocking overhead
- High speed operation for large number of inputs

MICRO-35 Tutorial PAMs, 2002

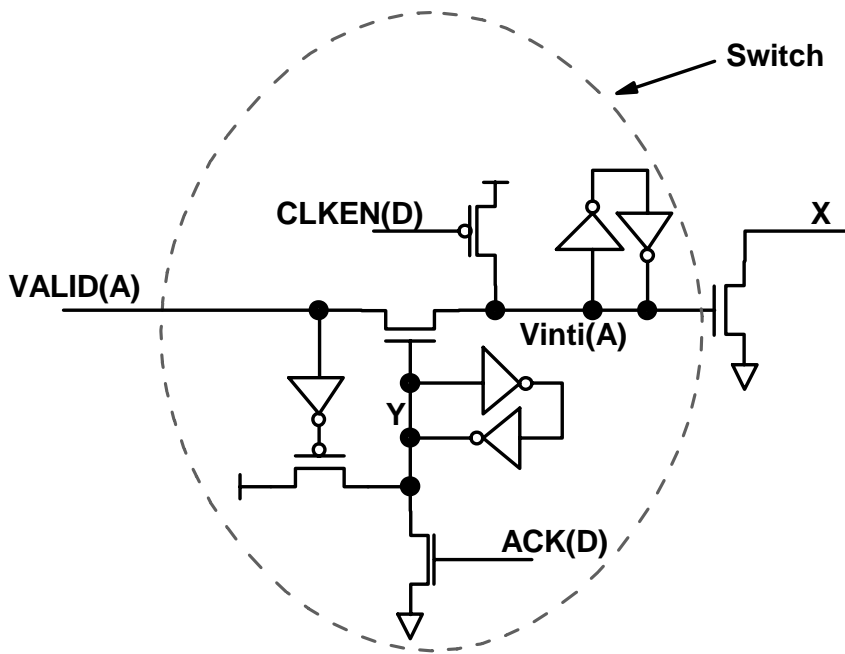
IBM T. J. Watson Research Center and university partners



Local Clock Strobe Circuit

MICRO-35 Tutorial PAMs, 2002

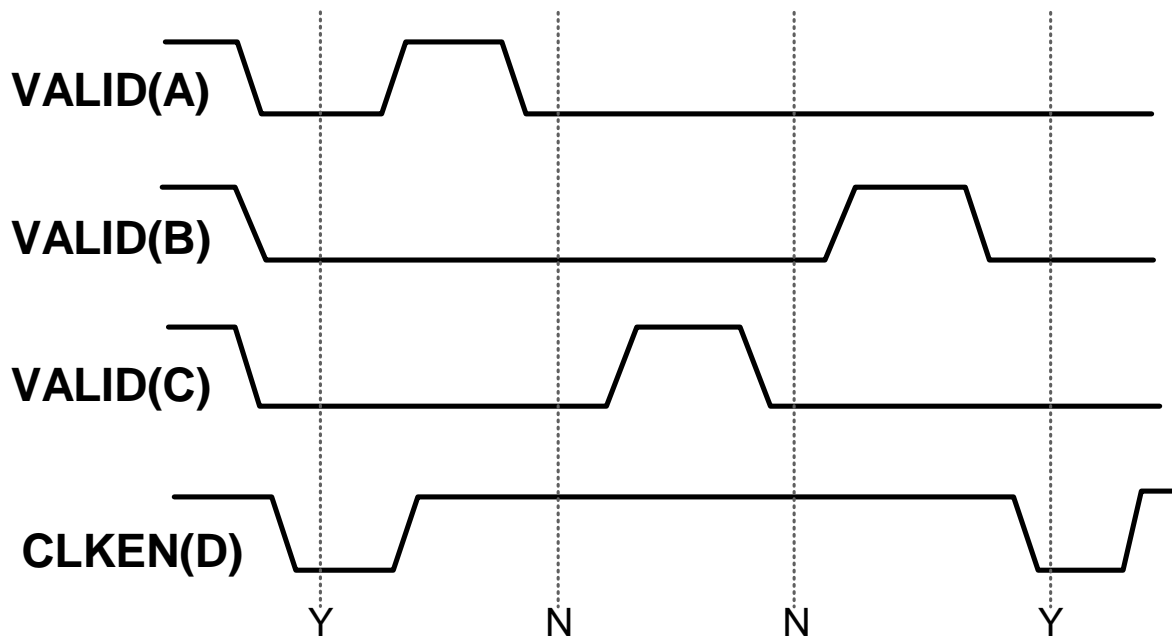
IBM T. J. Watson Research Center and university partners



Strobe Circuit Switch

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

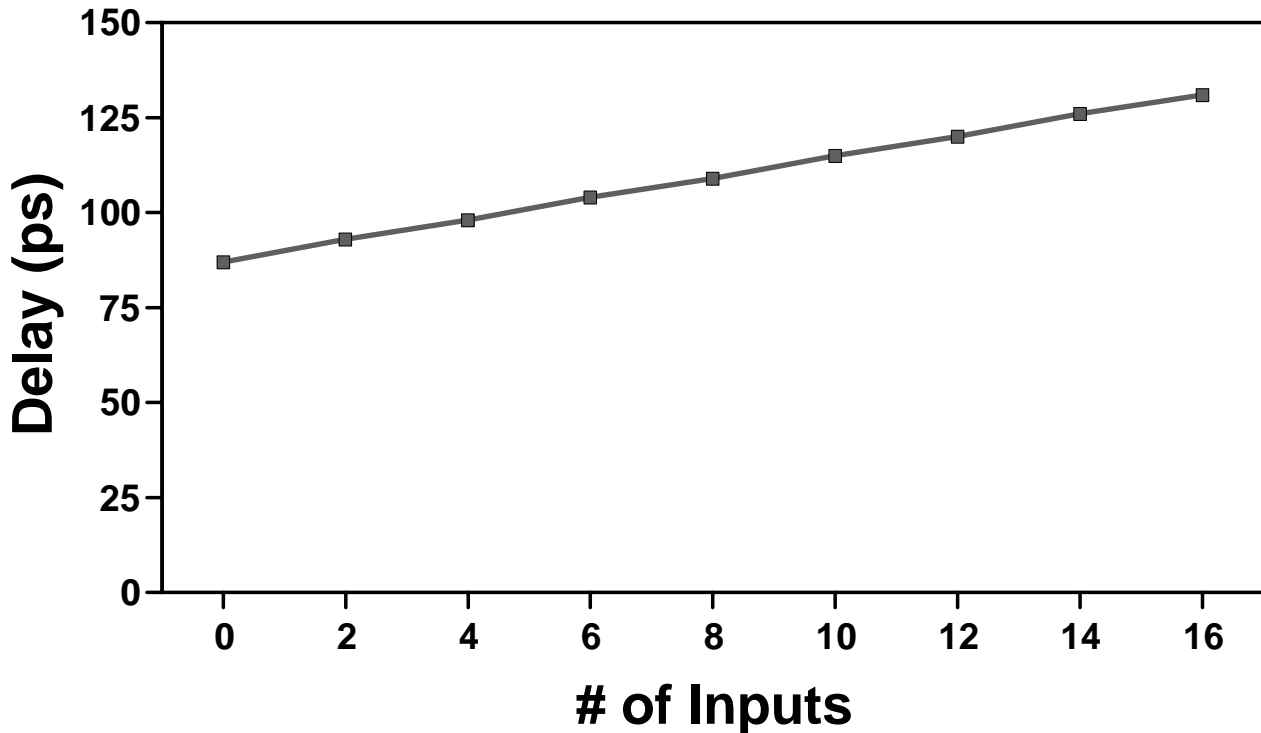


Strobe Circuit Unique "AND" Function

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

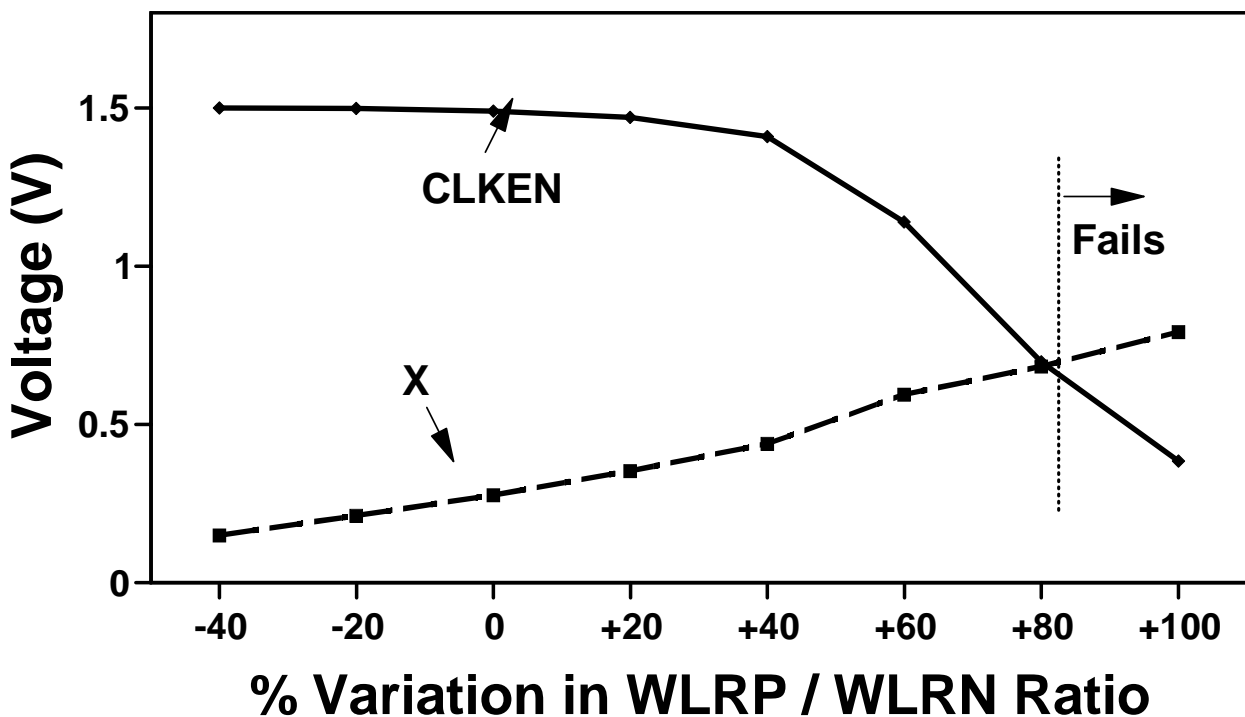
Strobe Delay versus # of Inputs



MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

Sensitivity Analysis with Device Variations

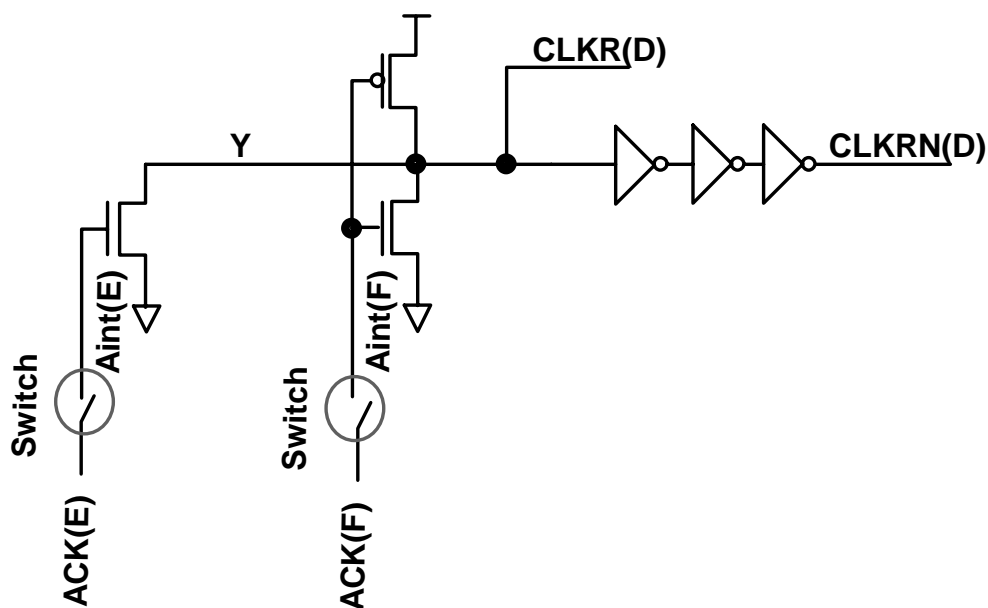


MICRO-35 Tutorial PAMs, 2002

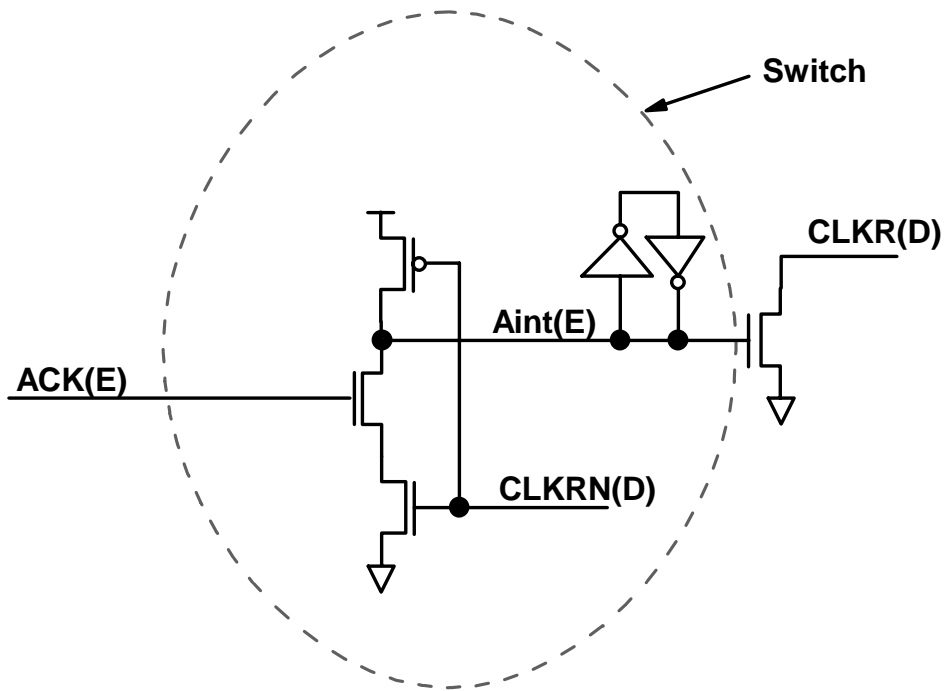
IBM T. J. Watson Research Center and university partners

Reset

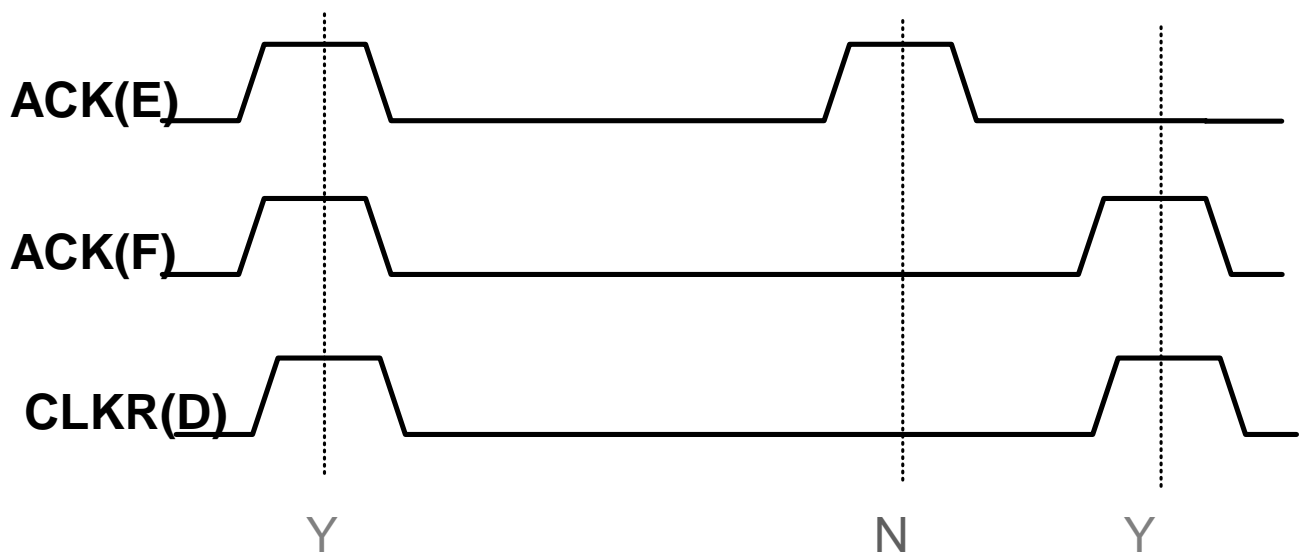
- Combines the function of a static NOR and an input switch
- Performs unique cycle dependent AND function on the ACK signals
- High speed for high-fan is achieved
- Resets the Valid circuit each asynchronous cycle



Reset Circuit



Reset Circuit Switch



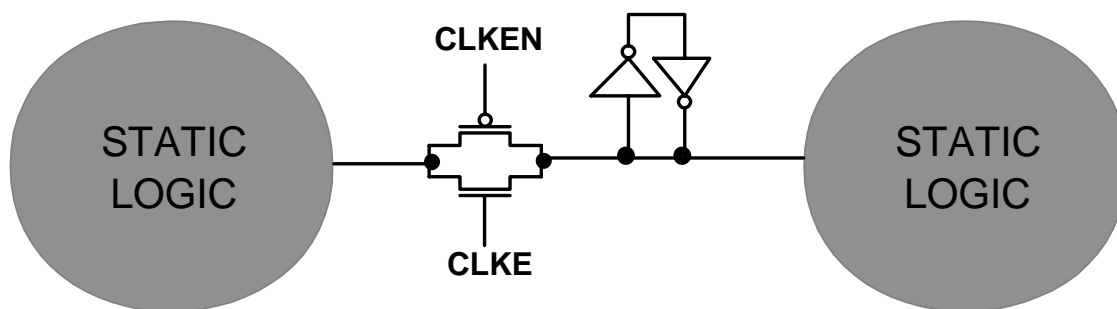
Unique Cycle Dependent "AND" Function

Latch

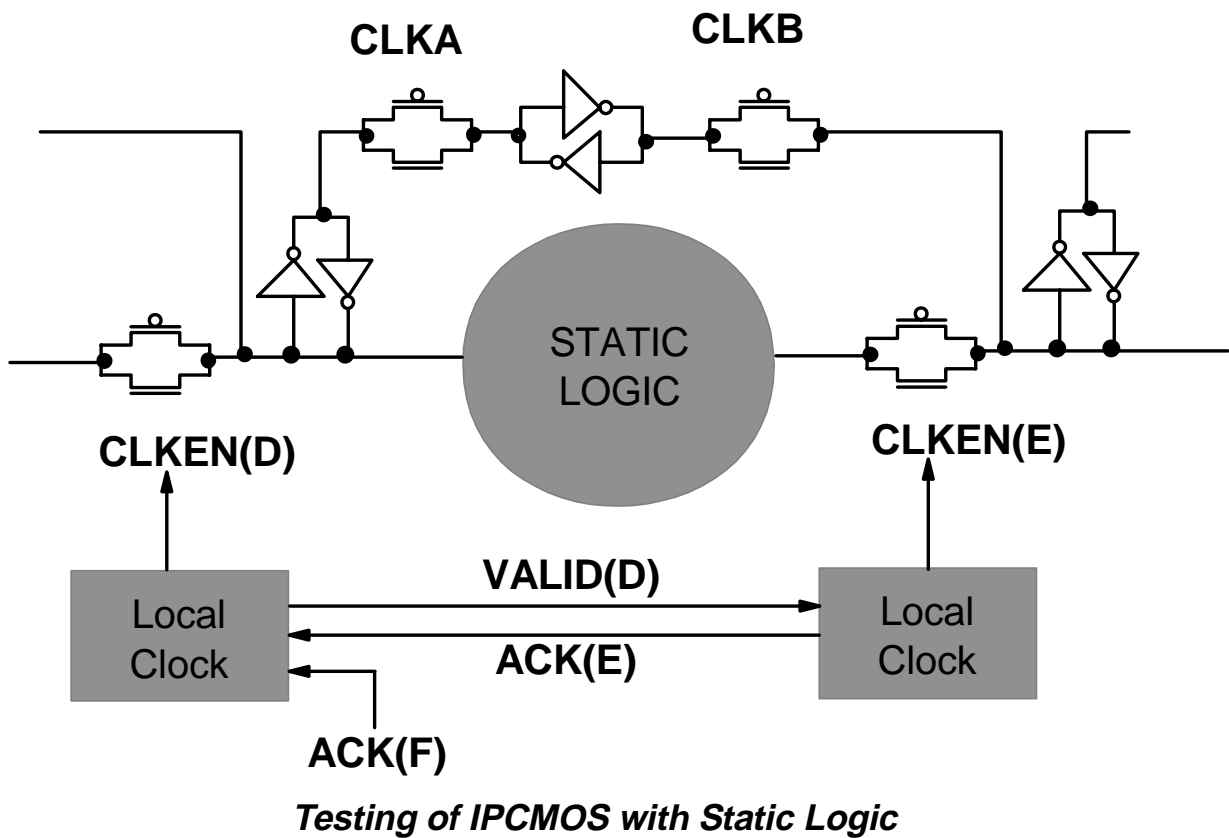
- Adds extremely small delay to logic path
- Single stage - not master / slave
 - ▶ Possible because adjacent latch stages are not enabled simultaneously
 - ▶ Latch enabled only when data valid
- Simple
- Simultaneous capture and launch
- Dynamic and static single rail and dual rail versions

MICRO-35 Tutorial PAMs, 2002

IBM T. J. Watson Research Center and university partners

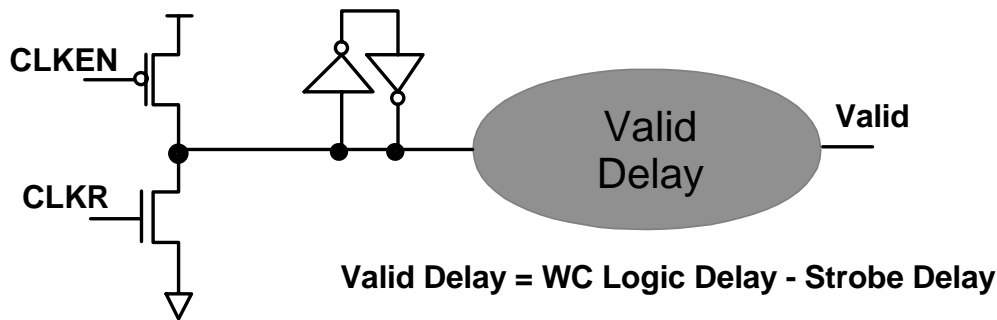


***Latch for Static
Logic***



Data Valid

- Data valid initiated by CLKEN and reset by CLKR
- Timing emulates slowest data path minus strobe delay
- One valid needed per group of data outputs
- Critical timing signal
- Valid delay on test site made adjustable over wide range



Valid Circuit

Results

- Local clocks for a multiplier function implemented in 0.18 bulk CMOS technology
- High frequency operation
 - ▶ 4.5GHz under best case conditions
 - ▶ 3.3GHz under typical conditions
- Extremely robust operation, insensitive to
 - ▶ Power Supply Voltage
 - ▶ Temperature
 - ▶ Parametrics (L_{eff} , V_t , ...)

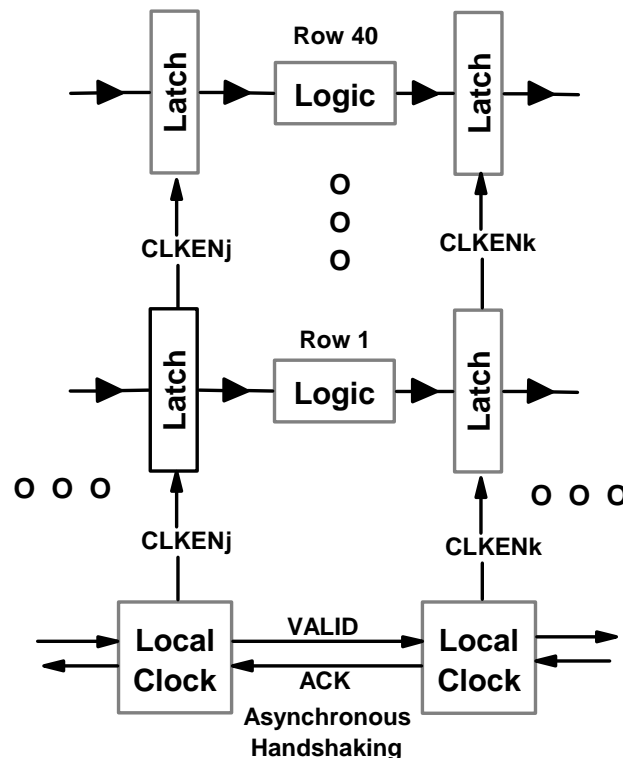
CMOS Technology Features

Power supply	1.5V
Gate oxide thickness	2.8nm
n channel L_{eff}	0.096 μ m
n channel threshold	0.355V
p channel L_{eff}	0.12 μ m
p channel threshold	0.305V
Low threshold device delta	0.07V
Minimum lithographic image	0.18 μ m
4 - 6 levels of metal	Copper

Table I

MICRO-35 Tutorial PAMs, 2002

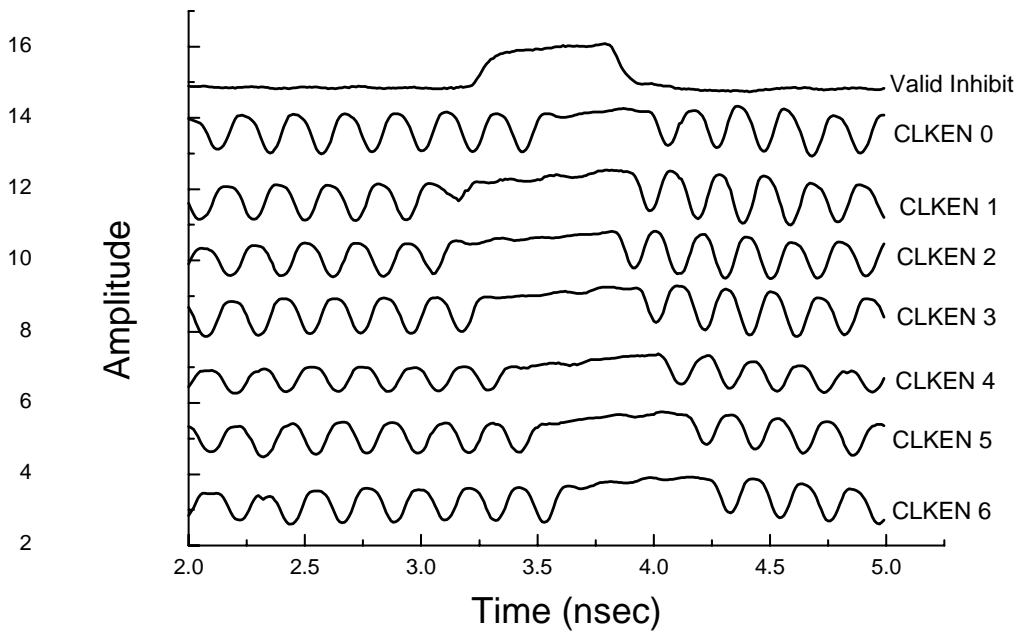
IBM T. J. Watson Research Center and university partners



Multiplier Core with Local Clocks

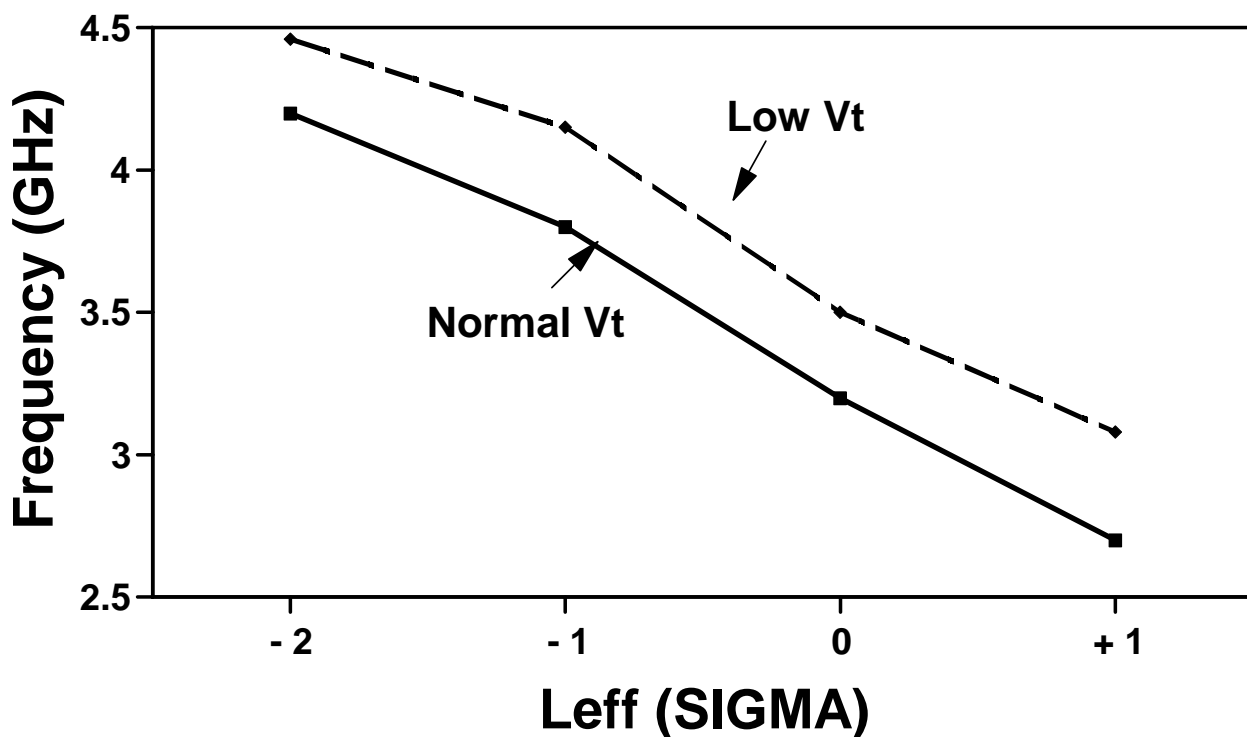
MICRO-35 Tutorial PAMs, 2002

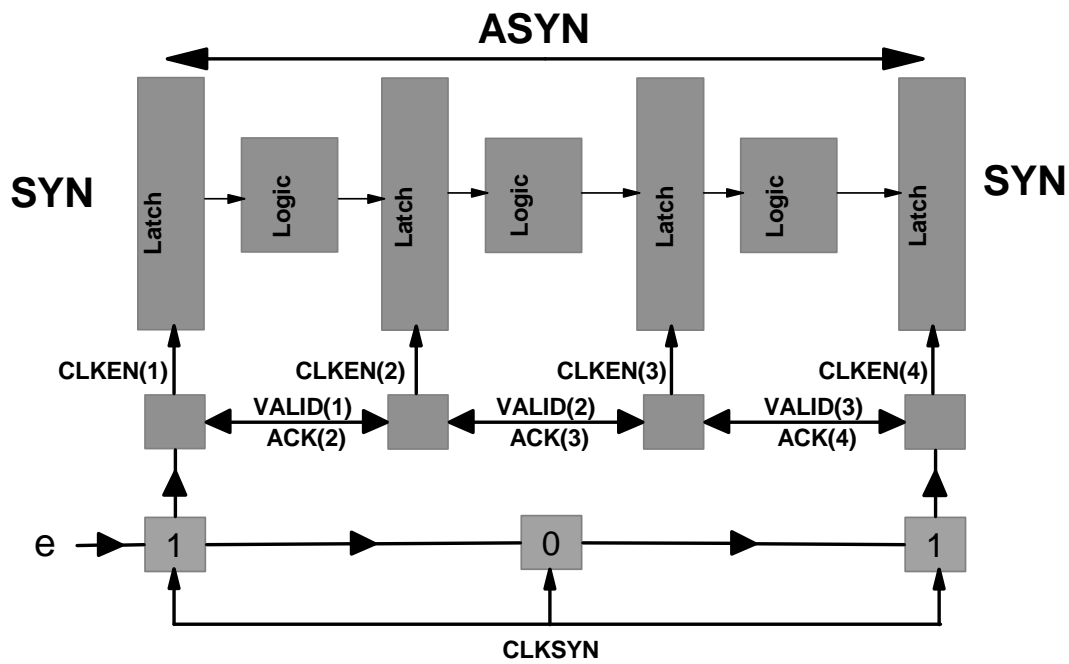
IBM T. J. Watson Research Center and university partners



Measured Local Clock Waveforms at 4.5GHz

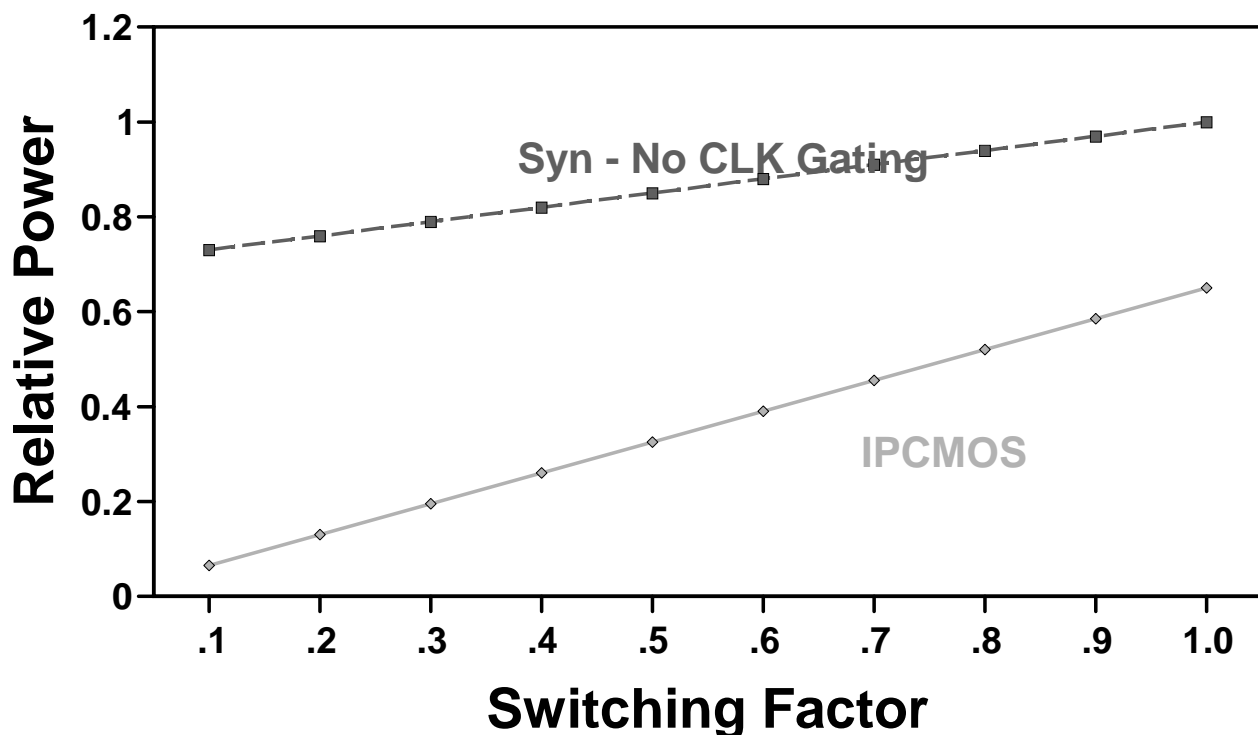
Frequency Versus Channel Length





Syn to Asyn to Syn Interfaces

Power versus Switching Factor (assuming 70% of power in clocks and latches)



Power and Noise

- IPCMOS offers significant power reduction
 - ▶ Clocks active only during an operation
 - ▶ Single stage register versus master/slave
- IPCMOS gives significant Ldi/dt noise reduction
 - ▶ Local clocks are staggered in time
 - ▶ Lower power results in lower current

IPCMOS Testing

- Stuck fault and ac testing possible
- Timing for ac tests generated by macro
 - ▶ Do not need high speed external clocks
 - ▶ Simple scan chain
- Timing control in data valid signal gives additional ac test coverage

Summary (IPCMOS)

- A syn to asyn to syn circuit technique suitable for multi-GHz operation has been developed
- Significant power reduction results from:
 - ▶ Enabling the local clocks only when data is valid
 - ▶ Reduced clock loading from the simplified latch structure
- Interlocked circuits deal with global timing issues
 - ▶ Delay variations from power supply noise
 - ▶ Delay variations from chip parametrics
- Helps alleviate the problem of stringent clock synchronization